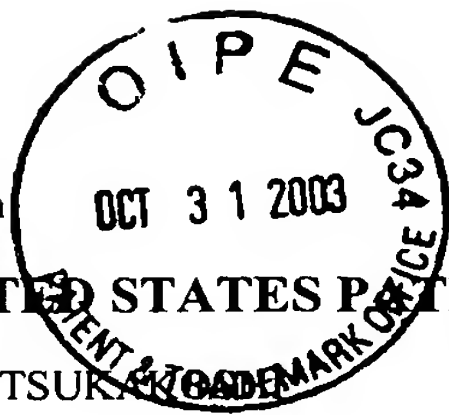


Docket No. 239720US90CONT/phh



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Toshio TSUKAGAWA

SERIAL NO: 10/608,032

GAU: 2121

FILED: June 30, 2003

EXAMINER:

FOR: IMAGE FORMING CHARACTERISTICS MEASURING METHOD, IMAGE FORMING CHARACTERISTICS ADJUSTING METHOD, EXPOSURE METHOD AND APPARATUS, PROGRAM AND STORAGE MEDIUM, AND DEVICE MANUFACTURING METHOD

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references, some of which are cited in the attached International Search Report listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).
- ☐ A credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☒ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).
- ☐ A credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		DOCKET NO. 239720US90CONT		SERIAL NO. 10/608,032	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toshio TSUKAKOSHI			
				FILING DATE June 30, 2003		GROUP 2121	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	6,248,486	06/19/2001	P. DIRKSEN, et al.			
	AB	2002/0008869 A1	01/24/2002	H. VAN DER LAAN, et al.			
	AC	2002/0036758 A1	03/28/2002	C. G. M. DE MOL, et al.			
	AD	2002/0191165 A1	12/19/2002	J. J. M. BASELMANS, et al.			
	AE	5,978,085	11/02/1999	A. H. SMITH, et al.			
	AF						
	AG						
	AH						
	AI						
	AJ						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AK	1 160 626	12/05/2001	EUROPE			
	AL	WO 00/31592 ✓	06/02/2000	WIPO			
	AM	1 128 217 ✓	08/29/2001	EUROPE			
	AN	10-154657 ✓	06/09/1998	JAPAN (with English Abstract)			X
	AO	2000-121491 ✓	04/28/2000	JAPAN (with English Abstract)			X
	AP	WO 99/60361 ✓	11/25/1999	WIPO (with English Abstract)			X
	AQ	1 079 223 ✓	02/28/2001	EUROPE			
	AR	11-118613 ✓	04/30/1999	JAPAN			X
	AS	6-235619 ✓	08/23/1994	JAPAN			X
	AT	5-296879 ✓	11/12/1993	JAPAN			X
	AU	2000-47103 ✓	02/18/2000	JAPAN			X
	AV	2000-331923 ✓	11/30/2000	JAPAN			X
	AW	11-233424	08/27/1999	JAPAN			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AX	D. G. FLAGELLO, et al., SPIE Microlithography Seminar, pages 1-14, " TOWARDS A COMPREHENSIVE CONTROL OF FULL-FIELD IMAGE QUALITY IN OPTICAL PHOTOLITHOGRAPHY ", March 1997					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							